

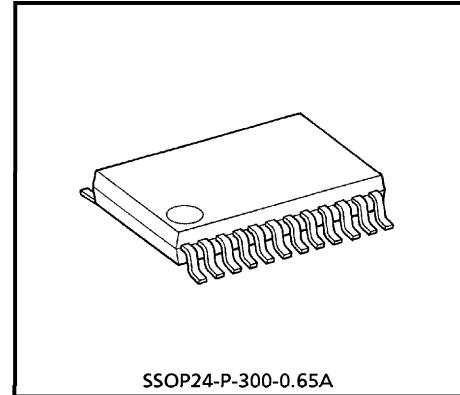
TOSHIBA BIPOLAR LINEAR INTEGRATED CIRCUIT SILICON MONOLITHIC

**TA31188FNG****FILTERLESS IF DETECTOR IC FOR CT1 CORDLESS TELEPHONE**

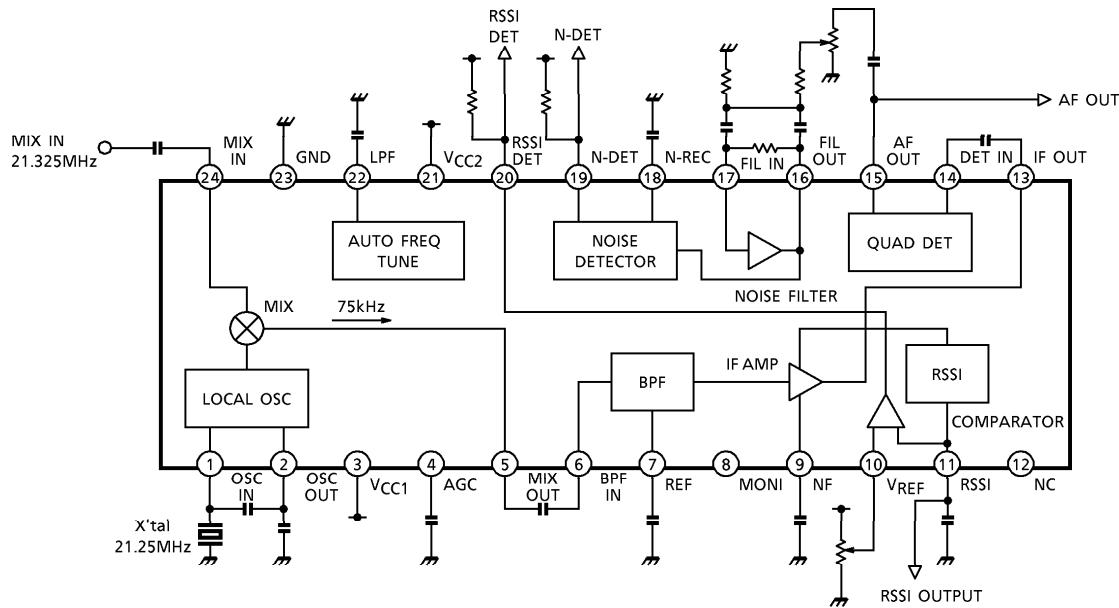
This IF IC is of channel selection filter in itself for cordless telephone and that realized to be able to eliminate the external parts extremely due to including external discriminator.

**FEATURES**

- Low voltage operation :  $V_{CC} = 1.8V \sim 5.5V$
- High sensitivity : 12dB sensitivity 16dB $\mu$ VEMF (50Ω Input)
- Built-in noise detector circuit
- RSSI function
- Small package : SSOP24 pin (0.65mm pitch)

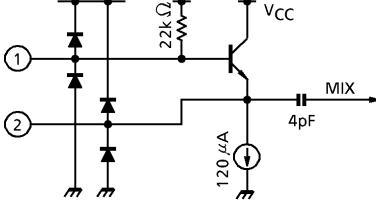
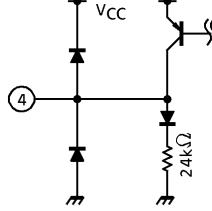
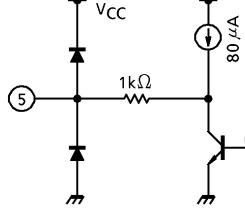
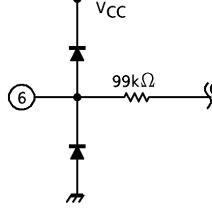
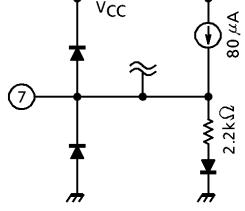


Weight : 0.14g (Typ.)

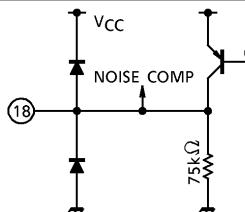
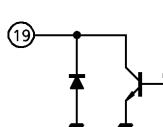
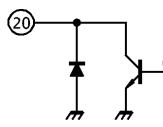
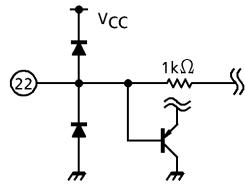
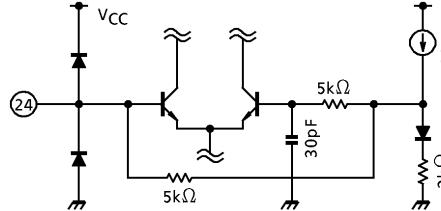
**BLOCK DIAGRAM**

: The TA31188FNG is Pb-Free Package

## PIN FUNCTION (The values of resistor and capacitor are typ.)

PIN No.	PIN NAME	FUNCTION	INTERNAL EQUIVALENT CIRCUIT
1	OSC IN	LOCAL OSC input / output terminals. Colpitts oscillator is formed by internal emitter follower and external crystal.	
2	OSC OUT	And external local signal injection is possible from pin 1 or pin 2.	
3	V <sub>CC1</sub>	Power supply terminal.	—
4	AGC	AGC terminal for MIX conversion gain. This terminal connects capacitor to GND.	
5	MIX OUT	MIX Output terminal. Output impedance is around 1.1kΩ.	
6	BPF IN	Internal BPF input terminal.	
7	REF	Internal BPF decoupling terminal for DC bias. This terminal connects capacitor to GND.	
8	MONI	Use at open as this terminal connects to internal circuit.	—

PIN No.	PIN NAME	FUNCTION	INTERNAL EQUIVALENT CIRCUIT
9	NF	IF AMP decoupling terminal for DC bias. This terminal connects capacitor to GND.	
10	V <sub>REF</sub>	Reference power supply terminal.	
11	RSSI	This terminal outputs DC level according to input signal level to IF AMP. Dynamic range is around 80dB.	
12	NC	Open terminal.	—
13	IF OUT	Output terminal of IF AMP.	
14	DET IN	QUAD DET input terminal.	
15	AF OUT	Demodulated output terminal. Output impedance is around 1.1kΩ.	
16	FIL OUT	FIL AMP input/ output terminal. Compose the BPF by putting the external capacitance and Resistance and this terminal connects to rectifire circuit internally by internal decoupling capacitance.	
17	FIL IN		

PIN No.	PIN NAME	FUNCTION	INTERNAL EQUIVALENT CIRCUIT
18	N-REC	Rectify to direct current by external capacitance after amplifying the FIL AMP output to around 20dB.	
19	N-DET	Operating as comparator of N-REC terminal output voltage, and doing the judgement of NOISE DET. Hysteresis width is around 100mV and this terminal is from open collector.	
20	RSSI DET	This terminal outputs the result of comparator between V <sub>REF</sub> terminal input voltage and RSSI terminal output voltage. If V <sub>REF</sub> is less than RSSI, then RSSI DET is set to "L". This output is from open collector.	
21	V <sub>CC2</sub>	Power supply terminal for AUTO FREQ TUNE block.	—
22	LPF	Decoupling terminal of the circuit, that tuning the internal BPF f <sub>0</sub> automatically. This terminal connects capacitor to GND.	
23	GND	GND terminal.	—
24	MIX IN	1st IF signal input terminal.	

## DESCRIPTION

## 1. BPF (band pass filter)

1st IF from MIX input terminal is converted to 2nd IF 75kHz by mixing 2nd MIX and LOCAL OSC 21.250MHz to be input to BPF.

This BPF is of high Q with center frequency  $f_0 = 75\text{kHz}$ ,  $-6\text{dB}$  band width  $BW = 19\text{kHz}$  and attenuation  $63\text{dB}$  and these factors are cause of selectivity characteristics and demodulation output distortion characteristics.

This IC is of automatic frequency tuning system that stabilize the center frequency  $f_0$  drift of internal BPF for 2nd IF by temprature and parameter tolerance and this function is executed by control circuit with internal clock as reference frequency from LOCAL OSC. Clock frequency signal source should be required high accuracy for 2nd local frequency as the signal source of refency clock 21.250MHz, because selectivity characteristics and demodulation output distortion characteristics depend on clock frequency.

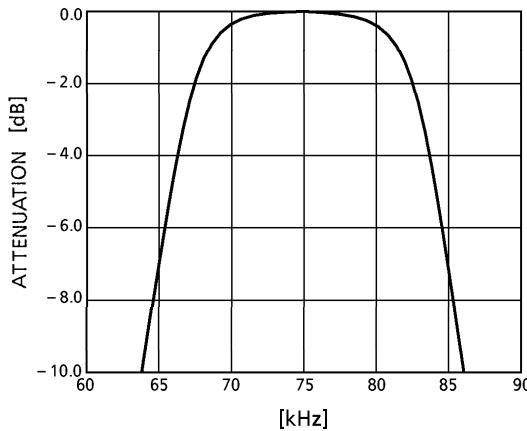


Fig.1 BPF characteristics

## 2. LOCAL OSC external injection method

Inputting from pin1 as shown in Fig.2, add resistor R21 to pin2 and set the input signal so that signal level at pin1 is  $95\sim 105\text{dB}\mu\text{V}$ . A built-in BUFFER amp minimizes leakage from MIX.

Inputting from pin2 as shown in Fig.3, set the injection level at pin2 between  $95\text{dB}\mu\text{V}$  and  $105\text{dB}\mu\text{V}$ .

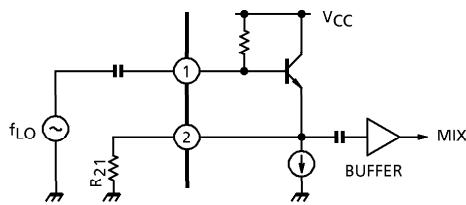


Fig.2

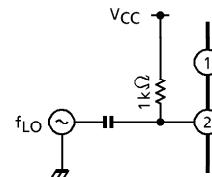


Fig.3

### 3. NOISE FILTER AMP

NOISE FILTER AMP can construct BPF as Fig.4. Setting constants follow as below equation (1)~(3).

$$(1) \quad f_0 = \frac{1}{2\pi \sqrt{R_1 (R_2 // R_3) C^2}}$$

$$(2) \quad G_V = R_1 / 2R_2$$

$$(3) \quad Q^2 = \frac{R_3}{4(R_2 // R_3)}$$

at  $R_2 \gg R_P$

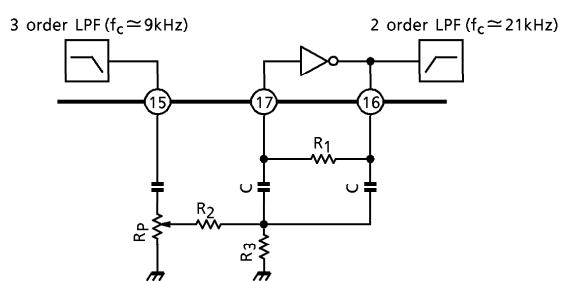


Fig.4

In case of the setting level of NOISE DET being low, NOISE DET may operate incorrectly in the cause of carrier leak components of IF frequency 75kHz.

In this case get the NOISE DET filter set to LPF to be able to eliminate carrier leak components.

$$(1) \quad f_0 = \frac{1}{2\pi R \sqrt{C_1 C_2}}$$

$$(2) \quad G_V = \frac{1}{2\omega C_2 R_4}$$

$$(3) \quad Q^2 = \frac{C_1}{4C_2}$$

at  $R_4 \gg R, \omega = 2\pi f$

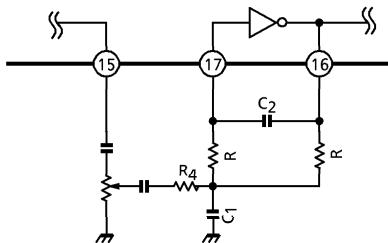


Fig.5

### 4. Noise detection rise time

The rise time is a proportion of time constant 7.5ms of the smoothing capacitor  $C_{181} = 0.1\mu F$  of the noise rectifier and internal resistor  $75k\Omega$ . Although decreasing the capacitance of  $C_{181}$  can shorten the rise time, note that the NOISE DET output fluctuation may increase. This should be taken into account before use.

## 5. RSSI COMPARATOR

The result of RSSI COMPARATOR is output to RSSI DET (20pin) by comparing RSSI terminal output voltage with  $V_{REF}$  terminal input voltage.

Hysteresis range is around 30mV. When  $V_{RSSI} > V_{REF}$ , RSSI DET is "L" level.

Reference voltage  $V_{REF}$  can be set by the external resistance  $R_{101}$ .

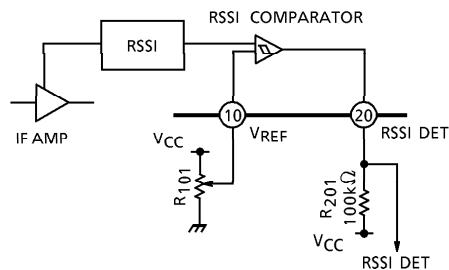


Fig.6

**MAXIMUM RATINGS (Ta = 25°C)**

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	V <sub>CC</sub>	7	V
Power Dissipation	P <sub>D</sub>	780	mW
Operating Temperature	T <sub>opr</sub>	-20~+70	°C
Storage Temperature	T <sub>stg</sub>	-55~+150	°C

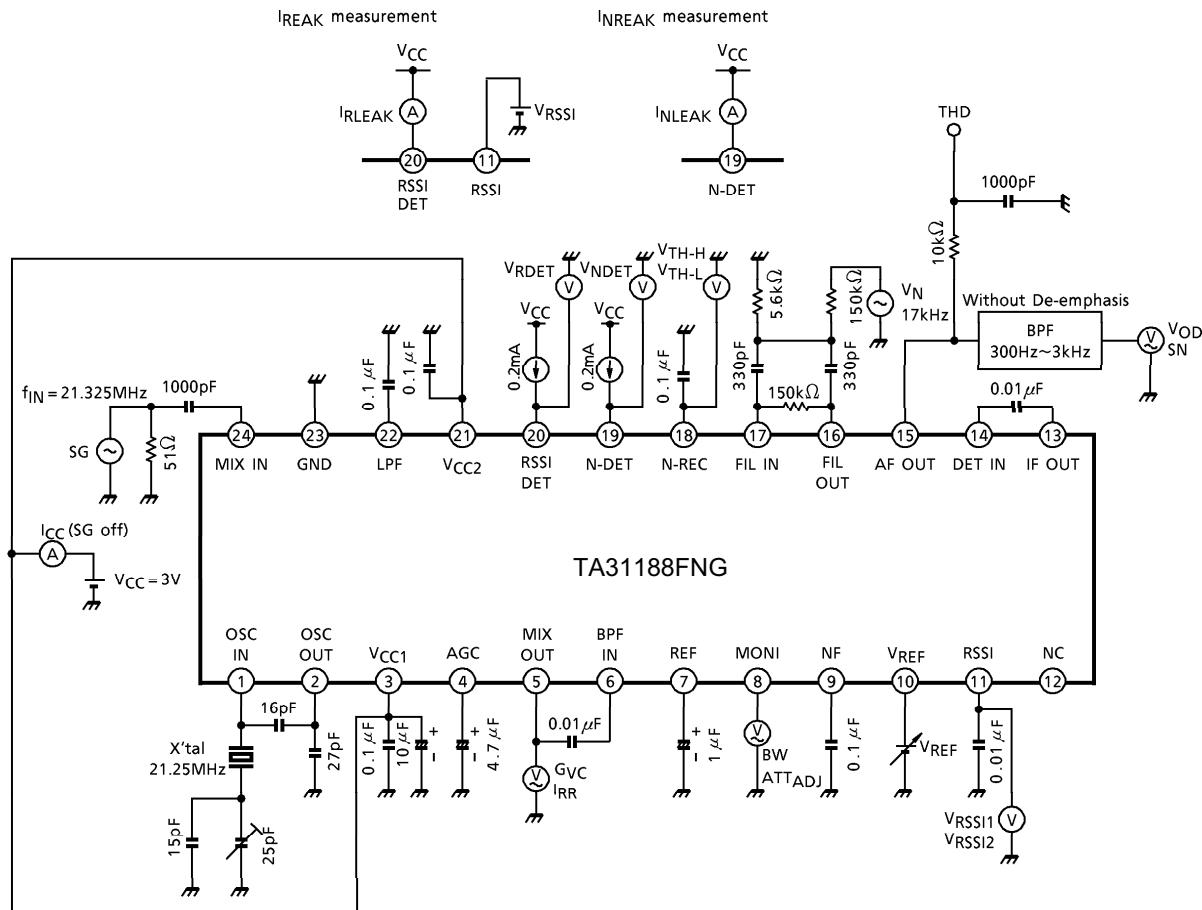
**ELECTRICAL CHARACTERISTICS** (Unless otherwise specified V<sub>CC</sub> = 3.0V, f<sub>IN</sub> = 21.325MHz, Δf = ±3kHz, f<sub>MOD</sub> = 1kHz, Ta = 25°C)

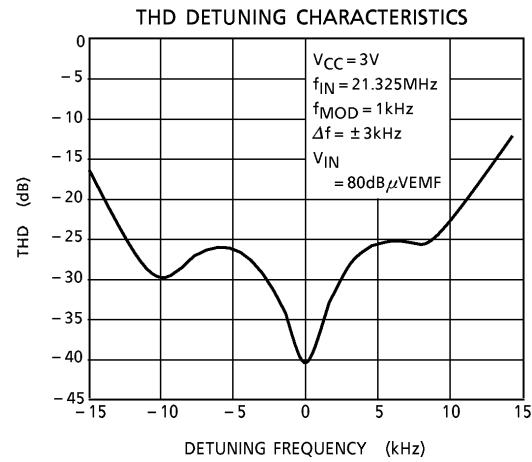
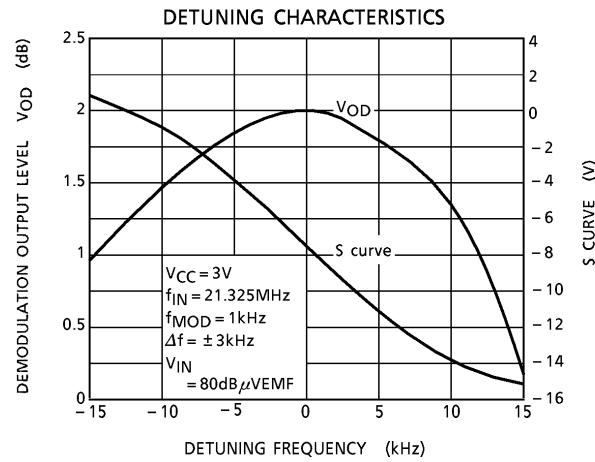
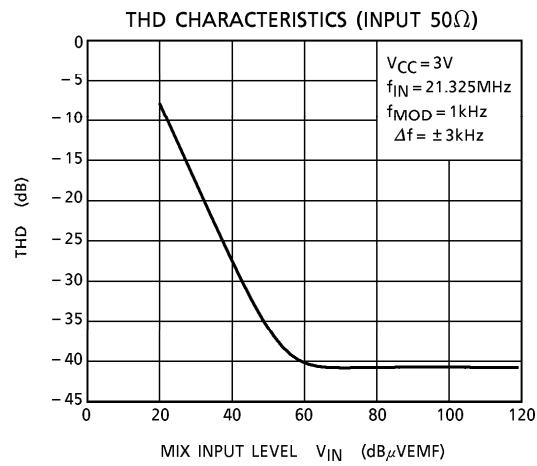
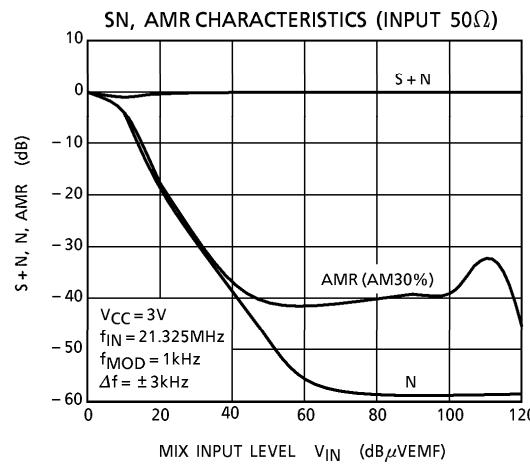
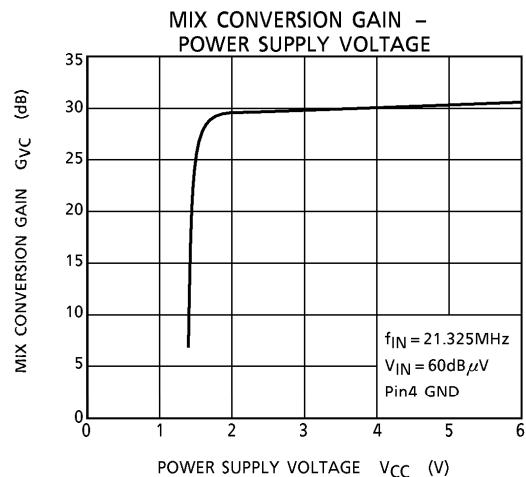
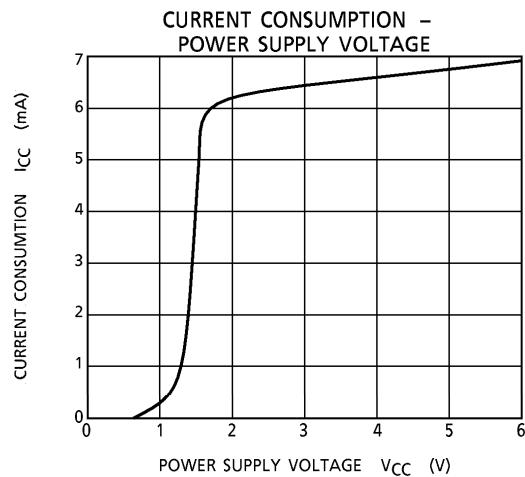
CHARACTERISTIC	SYMBOL	TEST CIR-CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Power Supply Voltage	V <sub>CC</sub>	—	—	1.8	3.0	5.5	V
Current Consumption	I <sub>CC</sub>	1	No Signal	4.5	6.5	8.5	mA
MIX Operating Frequency	f <sub>IN</sub>	—	—	—	21.325	—	MHz
MIX Image Rejection Ratio	I <sub>RR</sub>	1	V <sub>IN</sub> = 70dB <sub>μ</sub> VEMF, Pin4 GND	25	35	—	dB
MIX Conversion Gain	G <sub>VC</sub>	1	V <sub>IN</sub> = 60dB <sub>μ</sub> V, Pin4 GND	27	30	33	dB
MIX Intercept Point	I <sub>p</sub>	—	—	—	103	—	dB <sub>μ</sub> VEMF
MIX Input Impedance	R <sub>IN</sub>	—	—	—	5	—	kΩ
	C <sub>IN</sub>	—	—	—	3	—	pF
12dB Sensitivity	12dB SN	—	—	—	16	20	dB <sub>μ</sub> VEMF
Demodulation Output Level	V <sub>OD</sub>	1	V <sub>IN</sub> = 80dB <sub>μ</sub> VEMF	160	200	240	mV <sub>rms</sub>
SN Ratio	SN	1	V <sub>IN</sub> = 80dB <sub>μ</sub> VEMF	47	58	—	dB
AM Rejection Ratio	AMR	—	AM = 30%, V <sub>IN</sub> = 80dB <sub>μ</sub> VEMF	—	38	—	dB
Demodulation Output Distortion	THD	1	V <sub>IN</sub> = 80dB <sub>μ</sub> VEMF	—	-38	-32	dB
Demodulation Output Cut-off Frequency	f <sub>C</sub>	1	-3dB	3.4	5.5	—	kHz
Pass Band Width	BW	—	-6dB	—	19	—	kHz
Rejection Level at Adjacent Channel	ATTADJ	1	f <sub>SEP</sub> = ±25kHz, f <sub>MOD</sub> = 400Hz	55	63	—	dB
LOCAL OSC Input Level	V <sub>LO</sub>	—	—	95	100	105	dB <sub>μ</sub> V

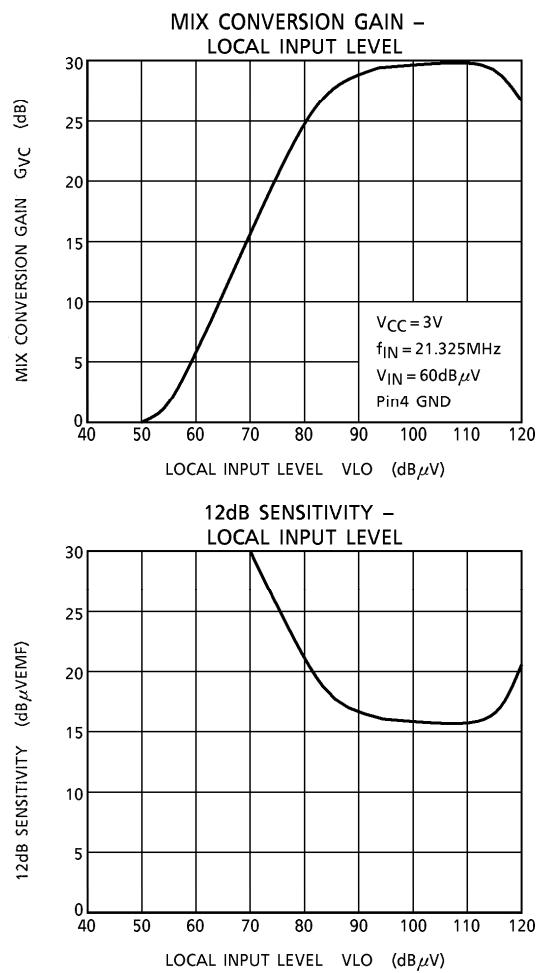
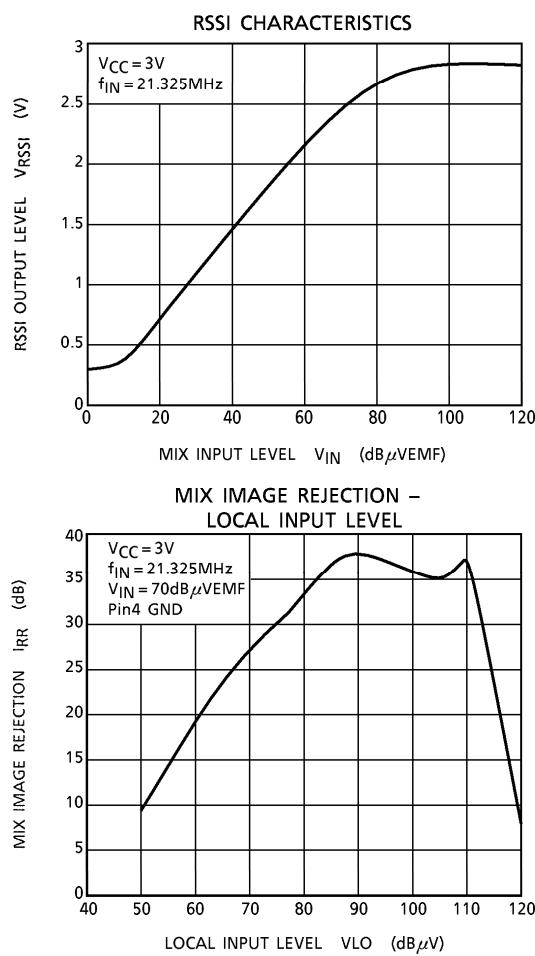
**ELECTRICAL CHARACTERISTICS** (Unless otherwise specified  $V_{CC} = 3.0V$ ,  $f_{IN} = 21.325MHz$ ,  $\Delta f = \pm 3kHz$ ,  
 $f_{MOD} = 1kHz$ ,  $T_a = 25^\circ C$ )

CHARACTERISTIC	SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
RSSI Output Voltage	$V_{RSSI1}$	1	$V_{IN} = 15dB\mu VEMF$	—	—	1	V
	$V_{RSSI2}$		$V_{IN} = 20dB\mu VEMF$	0.45	0.75	1.05	V
	$V_{RSSI3}$		$V_{IN} = 75dB\mu VEMF$	2.2	2.6	3.0	V
RSSI COMPARATOR Reference Input Range	$V_{REF}$	—	—	0.3	—	$V_{CC} - 1$	V
RSSI COMPARATOR Hysteresis Width	$V_{HYS}$	—	—	—	30	—	mV
RSSI COMPARATOR Output Voltage	$V_{RDET}$	1	$I_{SINK} = 0.2mA$	—	0.1	0.5	V
RSSI COMPARATOR Output Leak Current	$I_{RLEAK}$	1	$V_{RDET} = V_{CC}$ , $V_{RSSI} > V_{REF}$	—	0	5	$\mu A$
NOISE DET Output Voltage	$V_{NDET}$	1	$I_{SINK} = 0.2mA$	—	0.1	0.5	V
NOISE DET Output Leak Current	$I_{NLEAK}$	1	$V_{NDET} = V_{CC}$	—	0	5	$\mu A$
Noise Comparator Detect Level	$V_{TH-H}$	1	—	—	0.5	0.7	V
	$V_{TH-L}$		—	0.3	0.4	—	V

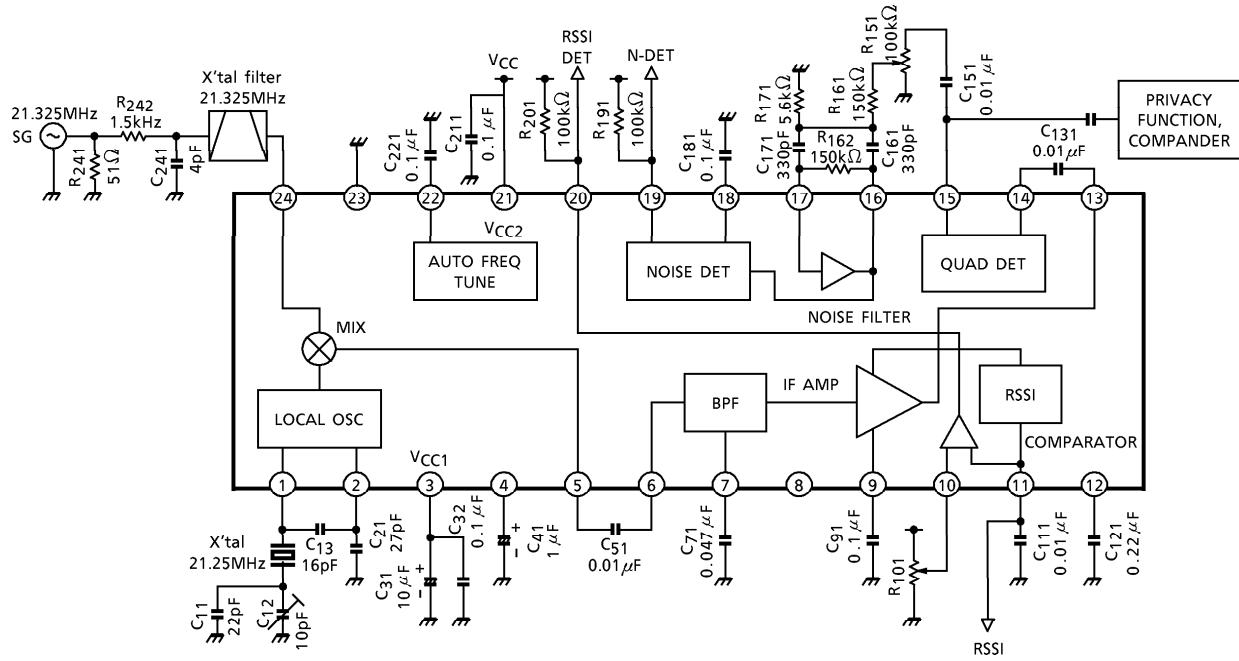
## TEST CIRCUIT 1





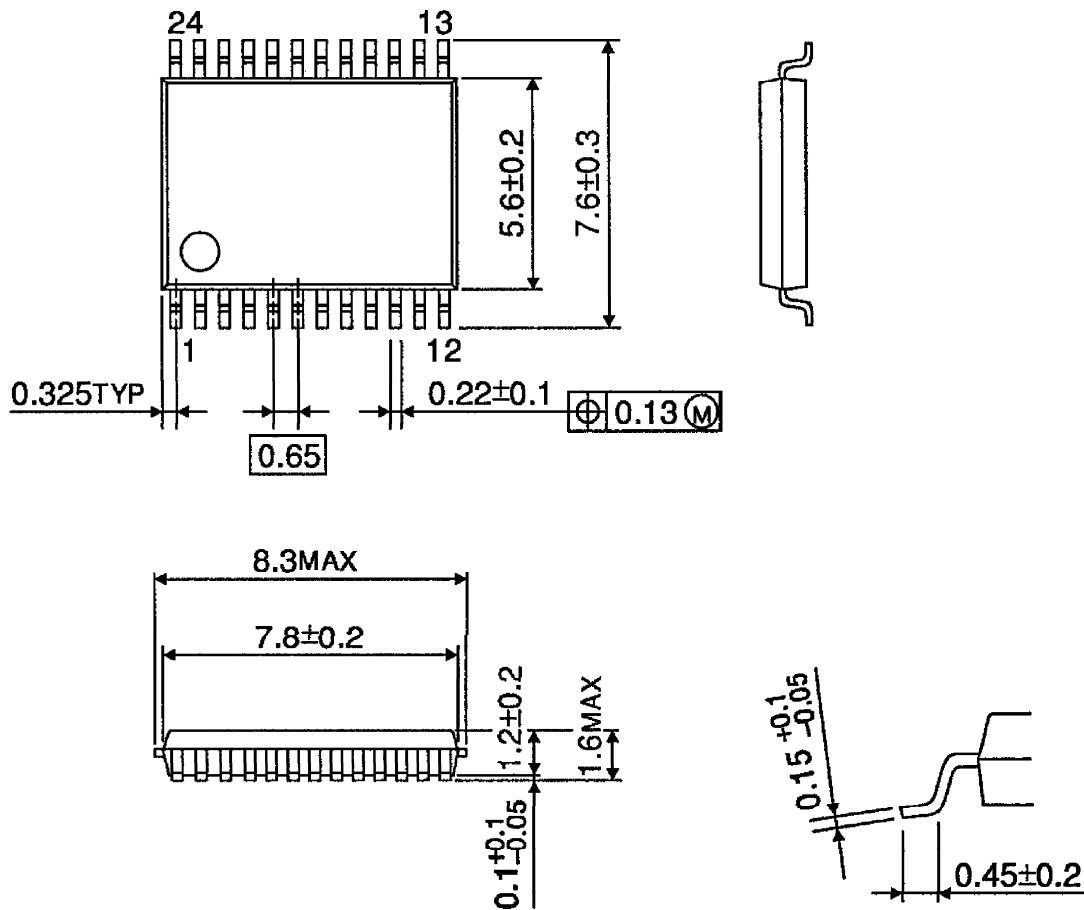


## APPLICATION CIRCUIT



**PACKAGE DIMENSIONS**  
SSOP24-P-300-0.65A

UNIT : mm



Weight : 0.14g (Typ.)

About solderability, following conditions were confirmed

Solderability

- (1) Use of Sn-63Pb solder bath
  - Solder bath temperature = 230
  - Dipping time = 5seconds
  - The number of times = once
  - Use of R-type flux
- (2) Use of Sn-3.0Ag-0.5Cu solder bath
  - Solder bath temperature = 245
  - Dipping time = 5seconds
  - The number of times = once
  - Use of R-type flux

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